

<b>Notice of References Cited</b>	Application/Control No. 09/804,158	Applicant(s)/Patent Under Reexamination KAWADA ET AL.	
	Examiner Kripa Sagar	Art Unit 1756	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-5,939,925	08-1999	Shibata et al.	327/355
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.